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LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)APPLICANT
Haruo YAMASHITA et al.

Date Submitted to PTO: March 9, 2006

FILING DATE
March 9, 2006

GROUP

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCL ASS	FILING DATE IF APPROPRIATE
	AA	2002/0006230	1/2002	Enomoto			
	AB	6,023,533	2/2000	Sano et al.			
	AC	2003/0152283	8/2003	Moriwaki			
	AD	2002/0085752	7/2002	Ohga			
	AE	6,624,828	9/2003	Dresevic et al.			
	AF	2002/0051001	5/2002	Kanai			
	AG	2003/0058252	3/2003	Matsuda et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCL ASS	TRANSLATION YES NO
	AH	2001-298619	10/2001	Japan			abstract
	AI	10-261077	9/1998	Japan			abstract
	AJ	2002-204372	7/2002	Japan			abstract
	AK	7-220066	8/1995	Japan			abstract
	AL	2000-57335	2/2000	Japan			abstract
	AM	2832954	10/1998	Japan			abstract
	AN	10-334218	12/1998	Japan			abstract
	AO	00/45365	8/2000	WO			abstract
	AP	2002-536677	10/2002	Japan			corresponds to AE and AO
	AQ	2002-95021	3/2002	Japan			abstract
	AR	10-65930	3/1998	Japan			abstract
	AS	1 189 457	3/2002	Europe			
	AT	2003-108109	4/2003	Japan			abstract
	AU						
	AV						

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

AW

/Christopher Leiby/
EXAMINER DATE CONSIDERED 01/28/2009

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /C.L./